

Advanced Topics in Software Engineering: Statistical transient analysis

Prof. Michele Loreti

Advanced Topics in Software Engineering *Corso di Laurea in Informatica (L31) Scuola di Scienze e Tecnologie*

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- performance estimation;
- (system) parameter estimation and optimisation;
- transient analysis;

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Basic ingredients:

- A model \mathcal{M} that describes our system as a random variable X(t) associating each time $t \in \mathbb{R}_{\geq 0}$ a vector of observations in \mathbb{R} ;
- A simulator function simulate_M(t) that, given a time t ∈ ℝ_{≥0} sample a path fragment/realisation/computation from M.

Statistical inference & Simulation... $_{\mathsf{Example}}$



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The model consists of four groups of agents:

- Suscettible;
- Exposed;
- Infected;
- Recovered.



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Events:

- One Suscettible becomes Exposed;
- One Exposed becomes Infected;
- One Infected becomes Recovered,

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Initial state: $(N - N_I, 0, N_I, 0)$

Transitions:

•
$$\left(S_E, \mathbf{1}_{S} + \mathbf{1}_{I}, \mathbf{1}_{E} + \mathbf{1}_{S}, \lambda_{e} \cdot \frac{X_{I}}{N} \cdot X_{S}\right)$$

• $\left(E_I, \mathbf{1}_{E}, \mathbf{1}_{E}, \lambda_{i} \cdot X_{I}\right)$
• $\left(I_R, \mathbf{1}_{I}, \mathbf{1}_{R}, \lambda_{r} \cdot X_{I}\right)$



We can use a simulator to study the fraction of citizens that are *infected* in a given time period:



We can use a simulator to study the fraction of citizens that are *infected* in a given time period:

- 1. Chose a deadline T;
- 2. Chose a number of replications *n*;
- 3. Chose the sampling time (time points where we register data):

$$D_{t_0},\ldots,D_{t_k}$$

where
$$t_i \in [0, T]$$
.
4. For each $i \in [0, n]$:
 $\sigma = \text{simulate}(T)$;
 $\forall t_i \in \{t_0, \dots, t_k\} : D_{t_i} = D_{t_i} \oplus \frac{\sigma_{\text{S}}(t_i)}{N}$.
5. Return $\overline{D_{t_0}}, \dots, \overline{D_{t_k}}$.

From theory to Practice...





We want to test a protocol that allow to us to elect a leader among a set of agents.



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Naive algorithm:

- 1. Each active agent randomly select a value in $\{0, 1\}$;
- 2. An agent survives and start another round if:
 - it has selected 0 and it sees another 0;
 - it has selected 1 and it sees either a 0 or a 1.
- 3. An agent that has selected 0 that sees a 1 becomes inactive.
- 4. If an agent does not see any other active agent it becomes the leader.
- 5. If a leader sees another active agent, it re-start its computation.

Example: Leader Election Question...



Question: How we can build a population model to describe this algorithm?

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Example: Leader Election



Population: A, S0, S1, I, L.

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Rules:





We can use simulation to estimate the number of actives, followers and leaders in the system.



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We can also estimate the probability to elect a single leader within \mathcal{T} time units.



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We can also estimate the probability to elect a single leader within T time units.

This is equivalent to estimate the probability of a Bernulli's distribution (like tossing a coin).

Recall...



Let X_1, \ldots, X_n be independent random variables distributed according the same Bernulli's distribution with parameter p, we have that:

$$Pr(|\overline{X}_n - p| > \epsilon) \le 2e^{-2n\epsilon^2}$$



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$$\begin{aligned} \Pr(|\overline{X}_n - p| > \epsilon) &\leq \delta \quad \Rightarrow \quad 2e^{-2n\epsilon^2} \leq \delta \\ &\Leftrightarrow \quad -2n\epsilon^2 \leq \log\left(\frac{\delta}{2}\right) \end{aligned}$$



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Given a threshold ϵ , and a probability δ , we can use this formula to compute the required number of iterations *n* to guarantee the probability.

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$$\Leftrightarrow n = \left\lceil \frac{\log\left(\frac{2}{\delta}\right)}{2\epsilon^2} \right\rceil$$

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Number of iterations...



$$n = \left\lceil \frac{\log\left(\frac{2}{\delta}\right)}{2\varepsilon^2} \right\rceil$$

	$\delta=0.1$	$\delta = 0.01$	$\delta = 0.001$
$\varepsilon = 0.1$	149	265	381
$\varepsilon = 0.01$	14979	26492	38005
$\varepsilon = 0.01$	1497867	2649159	3800452

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A path (or *realisation*) π of a stochastic process is a sequence of the form:

 $s_0 t_0 s_1 t_1 \dots s_n t_n \dots$

where each $s_i \in \mathbb{R}^k$.



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Let $\phi, \psi : \mathbb{R}^k \to \{\top, \bot\}$ be two predicates and $t \in \mathbb{R}_{\geq 0}$, we let:

 $\mathcal{R}(\phi, t, \psi) = \{\pi | \exists t' \leq t : \psi(\pi[t']) = \top \land \forall t'' < t' : \phi(\pi[t'']) = \top \}$



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N.B. For any ϕ , t and ψ , $\mathcal{R}(\phi, t, \psi)$ is measurable!

 $Pr(\mathcal{R}(\phi, t, \psi))$ is the probability to reach within t time units a configuration satisfying ψ while only configurations satisfying ϕ are traversed.

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1.
$$n = \left\lceil \frac{\log\left(\frac{2}{\delta}\right)}{2\varepsilon^2} \right\rceil$$

2.
$$sum = 0$$

3. for *n* times:

• $\pi = simulate(\mathcal{M})$ • if $\pi \in \mathcal{R}(\phi, t, \psi)$ then sum = sum + 1

4. return $\frac{sum}{n}$

From theory to practice...



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We can be also interested in the approximation of the function:

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Function $\rho_{\psi,\psi}$ describes how the probability to reach ψ (it is the CDF of the random variable $Y \leq t$):



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Function $\rho_{\psi,\psi}$ describes how the probability to reach ψ (it is the CDF of the random variable $Y \leq t$):

1.
$$n = \left\lceil \frac{\log\left(\frac{2}{\delta}\right)}{2\varepsilon^2} \right\rceil$$

2.
$$\mathcal{D} = \emptyset$$

3. for *n* times:

$$\pi = simulate(\mathcal{M}, t)$$

$$if \ \min_{t'} \pi \in \mathcal{R}(\phi, t', \psi) \neq \bot \text{ then } \mathcal{D} \uplus \{t'\}$$

$$4. \text{ return } \lambda x. \frac{|\{t' \le x | x \in \mathcal{D}|\}}{|t'|}$$

n



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$$H_0: p = p_0$$



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• $p > p_0$ • $p \le p_0$

The null hypothesis is:

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$$H_0: p = p_0$$

We specify two alternative hypothesis:

•
$$H_{+1}: p > p_0$$

• $H_{-1}: p < p_0$



Warning: H_0 cannot be proved correct since we cannot prove statistically that $p \neq p_0$.



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Note that Pr[X = 1] = p!



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We can consider the variable $Z_N = S_N - Np_0$:



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We can observe that...

- when $Z_N >> 0$, we have a strong evidence for H_{+1} ;
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• when $Z_N >> 0$, we have a strong evidence for H_{+1} ;

• when $Z_N \ll 0$, we have a strong evidence for H_{-1} . More in general we can identify in $\mathbb{R} \times \mathbb{R}$:



Fixed sample size tests

Sequential tests

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Two kind of tests can be considered:

- Fixed sample size tests: the decision is taken after an a-priori determined number of samples;
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- Fixed sample size tests: the decision is taken after an a-priori determined number of samples;
- Sequential tests: sampling potentially continue until a decision is reached.

For sequential tests the goal will be to identify two functions I(N) and u(N) that denote the borders $\mathcal{L} - \mathcal{NC}$ and $\mathcal{U} - \mathcal{NC}$.



To provide a measure (in terms of probability) of the error, the following events is considered:

$$\begin{array}{rcl} A_{+1} &=& \{ \operatorname{reach} \mathcal{U} \text{ before } \mathcal{L} \text{ or } \mathcal{I} \} \\ A_{-1} &=& \{ \operatorname{reach} \mathcal{L} \text{ before } \mathcal{U} \text{ or } \mathcal{I} \} \\ A_{0} &=& \{ \operatorname{reach} \mathcal{I} \text{ or stay in } \mathcal{NC} \} \\ \neg A_{+1} &=& A_{-1} \cup A_{0} \\ \neg A_{-1} &=& A_{+1} \cup A_{0} \end{array}$$



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We can impose the following conditions on false positive:

• $Pr(A_{+1}|\neg H_{+1}) \le \alpha_1$ • $Pr(A_{-1}|\neg H_{-1}) \le \alpha_2$



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- $Pr(A_{+1}|\neg H_{+1}) \leq \alpha_1$
- $Pr(A_{-1}|\neg H_{-1}) \leq \alpha_2$

and false negative:

- $Pr(\neg A_{+1}|H_{+1}) \leq \beta_1$
- $Pr(\neg A_{-1}|H_{-1}) \leq \beta_2$



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and false negative:

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$$Pr(\neg A_{+1}|H_{+1}) \leq \beta_1 = \beta$$

•
$$Pr(\neg A_{-1}|H_{-1}) \leq \beta_2 = \beta$$



We will consider three criteria to judge tests:

• the correctness: we call a test correct if its probability of not drawing the correct conclusion is guaranteed to be smaller than α , where $1 - \alpha$ is the confidence level;



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- the correctness: we call a test correct if its probability of not drawing the correct conclusion is guaranteed to be smaller than α , where 1α is the confidence level;
- the power: as the probability that the test will eventually draw a conclusion, that is 1 Pr(A₀);



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- the correctness: we call a test correct if its probability of not drawing the correct conclusion is guaranteed to be smaller than α , where 1α is the confidence level;
- the power: as the probability that the test will eventually draw a conclusion, that is 1 Pr(A₀);
- the efficiency: the number of samples needed (in expectation) before a conclusion can be drawn.

Test classification...





I Tests whose probability of drawing a wrong conclusion exceeds α when $|p-p_0|$ is small



- I Tests whose probability of drawing a wrong conclusion exceeds α when $|p-p_0|$ is small
- II Tests whose probability of drawing no conclusion (or a wrong conclusion) exceeds β when $|p p_0|$ is small.



I Tests whose probability of drawing a wrong conclusion exceeds α when $|p-p_0|$ is small

II Tests whose probability of drawing no conclusion (or a wrong conclusion) exceeds β when $|p - p_0|$ is small.

III Tests that are always correct and always draw a conclusion, at the cost of drawing an extremely large number of samples before reaching a conclusion when $|p - p_0|$ is small.

Test classification



	Class I	Class II	Class III
Risk when $p \approx p_0$	Correctness: wrong conclusion, i.e., error of first kind (& efficiency)	Power: no conclusion, i.e., error of second kind (& efficiency)	Efficiency: large running time
Parameter	Correctness-indifference level δ	Power-indifference level ζ	Guess y
Fixed sample size tests	Gauss-SSP	Gauss-CI	
		Chernoff-CI	
Mixed tests		Chow–Robbins	
Sequential tests	SPRT		Azuma
			Darling

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The Binomial and Gaussian confidence interval (l^*, u^*) is:

•
$$l^* = \Phi^{-1}(\alpha)\sqrt{N*p_0(1-p_0)}$$

• $u^* = \Phi^{-1}(1-\alpha)\sqrt{N*p_0(1-p_0)} = -l^*$
Binomial and Gaussian confidence intervals

binomialCaussianCl($\mathcal{M}, \alpha, \beta, p_0, \phi, t, \psi$):

- 1. $N = f(\beta)$ 2. $I^* = \Phi^{-1}(\alpha)\sqrt{N * p_0(1 - p_0)}$ 3. $\mu^* = -I^*$
- 4. *s* = 0
- 5. for *N* times:

•
$$\pi = simulate(\mathcal{M})$$

• if $\pi \in \mathcal{R}(\phi, t, \psi)$ then $z = z + 1$

- 6. if $s N * p_0 < l^*$ return \mathcal{L}
- 7. if $s N * p_0 > u^*$ return \mathcal{U}
- 8. return \mathcal{I}

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If p is close to p_0 large values for N are needed.



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If p is close to p_0 large values for N are needed.

binomialCaussianCI is a Type II test and we want to guarantee that:

•
$$Pr(\neg A_{+1}|H_{+1}) \leq \beta$$

• $Pr(\neg A_{-1}|H_{-1}) \leq \beta$

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Let us assume that $p = p_0 + \zeta$ ($\zeta > 0$).



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The probability of not being able to reject H_0 in favour of H_{+1} after drawing N samples is:

$$\Pr[\widehat{p_N} \le p_0 + \Phi^{-1}(1-\alpha)]$$

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For large values of N we can assume that $\widehat{p_N} = S_N/N$ is well approximated by a normal distributed random variable with:

- mean $p_0 + \zeta$
- and variance $\sigma^2 = (p_0 + \zeta)(1 p_0 \zeta)/N$.



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 and $\sigma_{H_0}^2 = p_0(1 - p_0)/N$:

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- mean $p_0 + \zeta$
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Let
$$\xi = \Phi^{-1}(1 - \alpha)$$
 and $\sigma_{H_0}^2 = p_0(1 - p_0)/N$:

$$\begin{aligned} \Pr[\widehat{p_N} \le p_0 + \xi \sigma_{H_0}] &= \Pr\left[\frac{\widehat{p_N} - p_0 - \zeta}{\sigma} \le \frac{\xi \sigma_{H_0} - \zeta}{\sigma}\right] \\ &= \Phi\left(\frac{\xi \sigma_{H_0} - \zeta}{\sigma}\right) \\ &= \Phi\left(\frac{\xi \sqrt{p_0(1 - p_0)} - \zeta \sqrt{N}}{\sqrt{(p_0 + \zeta)(1 - p_0 - \zeta)}}\right) \end{aligned}$$

To guarantee that $Pr(\neg A_{+1}|H_{+1}) \leq \beta$ we have:

$$\beta = \Phi\left(\frac{\xi\sqrt{p_0(1-p_0)} - \zeta\sqrt{N}}{\sqrt{(p_0+\zeta)(1-p_0-\zeta)}}\right)$$
$$N_G^+ = \left(\frac{\xi\sqrt{p_0(1-p_0)} - \Phi^{-1}(\beta)\sqrt{(p_0+\zeta)(1-p_0-\zeta)}}{\zeta}\right)^2$$

Analogously, we can compute N_G^- by assuming $p = p_0 - \zeta$ and computing the probability $Pr(\neg A_{-1}|H_{-1})$.

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Statistical transient analysis

To guarantee that $Pr(\neg A_{+1}|H_{+1}) \leq \beta$ we have:

$$\beta = \Phi\left(\frac{\xi\sqrt{p_0(1-p_0)} - \zeta\sqrt{N}}{\sqrt{(p_0+\zeta)(1-p_0-\zeta)}}\right)$$
$$V_G^+ = \left(\frac{\xi\sqrt{p_0(1-p_0)} - \Phi^{-1}(\beta)\sqrt{(p_0+\zeta)(1-p_0-\zeta)}}{\zeta}\right)^2$$

Analogously, we can compute N_G^- by assuming $p = p_0 - \zeta$ and computing the probability $Pr(\neg A_{-1}|H_{-1})$.

Finally, we let $N = \max\{N_G^+, N_G^-\}$.

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CI using Chernoff-Hoeffding bound

In this test the Chernoff-Hoeffding bound is used to compute the confidence interval:

$$\Pr[|\overline{X} - E[\overline{X}]| > \epsilon] \le 2e^{-2Nt^2}$$

chTest($\mathcal{M}, \alpha, \epsilon, p_0, \phi, t, \psi$)

1. $N = \frac{1}{2\epsilon^2} \log\left(\frac{2}{\alpha}\right)$

2.
$$s = 0$$

- 3. for N times:
 - $\pi = simulate(\mathcal{M})$ $if \ \pi \in \mathcal{R}(\phi, t, \psi) \text{ then } z = z + 1$
- 4. if $s N * p_0 < -\epsilon$ return \mathcal{L}
- 5. if $s N * p_0 > \epsilon$ return \mathcal{U}
- 6. return \mathcal{I}



Cl using Chernoff-Hoeffding bound Error probability



Let $p = p_0 + \zeta$ ($\zeta > 0$). We have that:

$$Pr[\overline{X} - p_0 < \varepsilon_N] = Pr[p_0 - \overline{X} > -\varepsilon_N] \\ = Pr[p_0 - \overline{X} + \zeta > \zeta - \varepsilon_N] \\ \le e^{-2N(\zeta - \varepsilon)^2}$$

CI using Chernoff-Hoeffding bound Error probability



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The worst-case number of samples outside the power-indifference region can be computed as:

$$N_C = rac{2\sqrt{\log(eta)\log(lpha)} - \log(lphaeta)}{2\zeta^2}$$

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Chernoff-Hoeffding vs Gaussian Cl $\alpha = \beta$



α	ζ	$p_0 = 0.5$		$p_0 = 0.2$	
		N _C	N_G	$\overline{N_C}$	N_G
0.05	0.1	600	259	600	189
	0.025	9,587	4,199	9,587	2,785
	0.01	59,915	26,265	59,915	17,056
0.025	0.1	738	372	738	273
	0.025	11,805	6,035	11,805	4,012
	0.01	73,778	37,752	73,778	24,540

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The sequential probability radio test (SPRT) is based on the idea to sequentially test which of the following two hypothesis is true:

- $H_{+1}: p \ge p_{+1}$
- $H_{-1}: p \ge p_{-1}$

where $p_{-1} < p_{+1}$.

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The hypotheses' likelihood ratio T_N is:

$$T_N = rac{
ho_{+1}^{S_N}(1-
ho_{+1})^{N-S_N}}{
ho_{-1}^{S_N}(1-
ho_{-1})^{N-S_N}}$$

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Small values of T_N speak in favour of H_{-1} , large values of T_N speak in favour of H_{+1} .

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• $l' = \alpha_1/(1 - \alpha_2)$ • $u' = (1 - \alpha_1)/\alpha_2$

we have that:

- $Pr[H_{-1}|H_{+1}] \le \alpha_2$
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We identify an indifference level δ and we set $p_{+1} = p_0 + \delta$ and $p_{-1} = p_0 - \delta$ and:

$$\bullet H_{+1}: p \ge p_0 + \delta$$

• $H_{-1}: p \ge p_0 - \delta$

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We can observe that instead of the test statistic T_N we could use:

$$\log T_N = q_1 S_N + q_2 N$$

where:

$$q_1 = \log\left(rac{p_{+1}(1-p_1)}{(1-p_{+1})p_{-1}}
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ight)$$

Finally:

$$l(N) = \frac{1}{q_1}(\log l' - q_2 N) - Np_0$$
$$u(N) = \frac{1}{q_1}(\log u' - q_2 N) - Np_0$$

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sequential Test $(\mathcal{M}, \alpha_1, \alpha_2, \delta, N_m, p_0, \phi, t, \psi)$

- 1. $q_1 = ...$
- 2. $q_2 = ...$
- 3. *s* = 0
- 4. *N* = 0
- 5. log T = 0
- 6. while $N < N_m$ do:
 - $\begin{array}{l} \pi = simulate(\mathcal{M}) \\ \text{if } \pi \in \mathcal{R}(\phi, t, \psi) \text{ then } s = s+1 \\ \text{if } N = N+1 \\ \text{iog}T = q_1 \cdot s q_2 \cdot N \\ \text{if } logT < l(N) \text{ return } \mathcal{L} \\ \text{if } logT > u(N) \text{ return } \mathcal{U} \end{array}$

7. return \mathcal{I}



To be continued...

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